Se	arc	h	No	te:	S	

Application/Control No.	Applicant(s)/Patent under Reexamination	_
10/657,150	CHIDA ET AL.	
Examiner	Art Unit	
Bing Q. Bui	2614	

	SEARCHED			
Class	Subclass	Date	Examiner	
379	211.01	10/15/2006	ВВ	
n	212.01			
"	213.01			
*	214.01			
п	218.02			

TNI	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
	<u> </u>			
	ŀ			

SEARCH (INCLUDING SEAF	SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR		
EAST search	10/15/2006	ВВ		
•				